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Future Development of Trustworthy Artificial Intelligence and Applications

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Deadline for manuscript submissions:

20 December 2024

Message from the Guest Editors

Issue solicits both fundamental Special applicational research that presents the latest advancements and challenges in the development of trustworthy Al. We welcome research that explores the technical and social dimensions of trustworthy AI, investigates the status quo vulnerabilities of AI systems, develops principled countermeasures to interpret Al decision-making and enhance AI accountability, and promotes the deployment of trustworthy AI in diverse fields

We invite submissions from researchers at various levels of their careers. Specific topics include the following:

- Vulnerability analysis in AI systems.
- Interpretable AI decision-making.
- Fairness and bias mitigation for AI systems.
- Privacy-preserving Al.
- AI ethics and value alignment.
- Human–Al interaction with trust and reliability.
- Hardware and algorithm co-design for robust Al.
- Al accountability through benchmarking.
- Trustworthy Al applications for realistic and highstake fields











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Message from the Editor-in-Chief

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